

INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Device embedding assembly technology –
Part 2-5: Guidelines – Implementation of a 3D data format for device embedded
substrate**

**Technologie d'ensemble avec appareil(s) intégré(s) –
Partie 2-5: Lignes directrices – Mise en œuvre d'un format de données 3D
pour un substrat avec appareil(s) intégré(s)**



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CONTENTS

FOREWORD.....	5
1 Scope.....	7
2 Normative references	7
3 Terms and definitions	7
4 Data definition	10
4.1 Flow chart design of device embedded substrate	10
4.2 Applicable range	11
4.2.1 Product.....	11
4.2.2 Process	12
4.3 Features	13
4.3.1 General	13
4.3.2 Device embedded substrate structure	13
4.3.3 SiP interposer structure	14
4.3.4 Virtual layer description	15
4.3.5 Terminal structure and embedded device structure including an SiP	15
4.3.6 Total design data of an SiP and device embedded substrate	15
4.4 Data description summary.....	16
4.4.1 Type of data and structures	16
4.4.2 File structure	18
4.5 3D expression.....	19
4.5.1 General	19
4.5.2 Coordinates	19
4.5.3 Position description	20
4.5.4 Relation between coordinate origin and board position	20
4.6 Layer concept	21
4.7 Substrate data	21
4.7.1 General	21
4.7.2 Layer map information	22
4.7.3 Device arrangement information	23
4.7.4 Basic figures.....	25
4.7.5 Net information	31
4.7.6 Artwork information.....	32
4.7.7 Package information	32
4.7.8 External port information.....	33
4.7.9 Internal port information.....	33
4.7.10 User expansion information	33
4.8 Defined data	33
4.8.1 General	33
4.8.2 Layer definition.....	33
4.8.3 Land definition	34
4.8.4 Via definition	35
4.8.5 Device definition	36
4.8.6 User expansion definition	37
5 Data organization and data description based on XML schema.....	38
5.1 General.....	38
5.2 Data organization of Example 1	38
5.3 Data description of layer stack-up	39

5.4	Data description of device	43
5.5	Data organization of layer	47
5.6	Data description of via	50
5.7	Data description of land	51
	Bibliography	53
	Figure 1 – Flow chart of design of device embedded substrate	11
	Figure 2 – General structure of device embedded substrate	12
	Figure 3 – Example of device embedded substrate structure	14
	Figure 4 – Examples of SiPs	14
	Figure 5 – Example of virtual layer description	15
	Figure 6 – Terminal structure	15
	Figure 7 – Structure of SiP on a device embedded substrate	16
	Figure 8 – Data structure	18
	Figure 9 – One file structure (recommended)	19
	Figure 10 – Two file structure	19
	Figure 11 – Definition of coordinates	20
	Figure 12 – Position definition	20
	Figure 13 – Relation between coordinates and board position	21
	Figure 14 – Layer concept	21
	Figure 15 – Layer construction	22
	Figure 16 – Simplified layer construction	23
	Figure 17 – Layer definition of pad connection	24
	Figure 18 – Layer definition of via connection	24
	Figure 19 – Rotation direction on <i>X</i> , <i>Y</i> , and <i>Z</i> axes	25
	Figure 20 – Point	26
	Figure 21 – Area	27
	Figure 22 – Lines	27
	Figure 23 – Letters	28
	Figure 24 – Letter shape	28
	Figure 25 – Bonding wire information	29
	Figure 26 – Semi-sphere	29
	Figure 27 – Truncated pyramid	30
	Figure 28 – Via	30
	Figure 29 – Device definition	31
	Figure 30 – Group	31
	Figure 31 – Data structure of net information	32
	Figure 32 – Relation of layer definition data	34
	Figure 33 – Land definition	35
	Figure 34 – Relation between hole information and land information	36
	Figure 35 – Device with internal connection information	37
	Figure 36 – Device without internal connection information	37
	Figure 37 – Cross sectional view of Example 1	38
	Figure 38 – Data organization of Example 1	38

Figure 39 – Data description of Example 1	39
Figure 40 – Layer structure of Example 1	40
Figure 41 – Data description of layer stack-up	42
Figure 42 – Configuration of device 1	43
Figure 43 – Data description of device 1	44
Figure 44 – Configuration of device 2	45
Figure 45 – Data description of device 2	46
Figure 46 – Layer view of Example 1	48
Figure 47 – Data description of layers	50
Figure 48 – Type of vias	51
Figure 49 – Data description of vias	51
Figure 50 – Type of lands	52
Figure 51 – Data description of lands	52
Table 1 – Required information	13
Table 2 – List of data	17

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DEVICE EMBEDDING ASSEMBLY TECHNOLOGY –

**Part 2-5: Guidelines – Implementation of a 3D data format
for device embedded substrate**

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International Standard IEC 62878-2-5 has been prepared by IEC technical committee 91: Electronics assembly technology.

This bilingual version (2020-01) corresponds to the monolingual English version, published in 2019-09.

This first edition cancels and replaces IEC PAS 62878-2-5 published in 2015. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) the title has been changed to "Implementation of a 3D data format for device embedded substrate" from "Requirements of design data format for device embedded substrate";
- b) the scope of this implementation has changed to not include SiPs.

The text of this International Standard is based on the following documents:

CDV	Report on voting
91/1557/CDV	91/1589/RVC

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

The French version of this standard has not been voted upon.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62878 series, published under the general title *Device embedding assembly technology*, can be found on the IEC website.

Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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DEVICE EMBEDDING ASSEMBLY TECHNOLOGY –

Part 2-5: Guidelines – Implementation of a 3D data format for device embedded substrate

1 Scope

This part of IEC 62878 specifies requirements based on XML schema that represents a design data format for device embedded substrate, which is a board comprising embedded active and passive devices whose electrical connections are made by means of a via, electroplating, conductive paste or printing of conductive material.

This data format is to be used for simulation (e.g. stress, thermal, EMC), tooling, manufacturing, assembly, and inspection requirements. Furthermore, the data format is used for transferring information among printed board designers, printed board simulation engineer, manufacturers, and assemblers.

This part of IEC 62878 applies to substrates using organic material. It neither applies to the re-distribution layer (RDL) nor to the electronic modules defined as M-type business model in IEC 62421.

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2 Normative references (standards.iteh.ai)

There are no normative references in this document.

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3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

3.1

artwork information

information that shows a SiP not included in net and figure data in board (symbol mark, inside of SiP, mould, spacer, remarks, etc.)

3.2

board information

total information of a device-embedded substrate, including embedded devices

3.3

chip stack

package of semiconductor chips stacked vertically

3.4

clearance

area around a through-hole where there is no conductor to prevent electrical connection between a large conductor area, such as that of a power supply or a ground and a plated through-hole

3.5

computer-aided manufacturing

CAM

interactive use of computer systems, programs, and procedures in various phases of a manufacturing process wherein the decision-making activity rests with the human operator and a computer provides the data manipulation functions

3.6

computer-aided design

CAD

interactive use of computer systems, programs, and procedures in the design process wherein the decision-making activity rests with the human operator and a computer provides the data manipulation function

3.7

DXF

data format for AutoCAD

Note 1 to entry: AutoCAD is the trade name of a product supplied by Autodesk®. This information is given for the convenience of users of this document and does not constitute an endorsement by IEC of the product named. Equivalent products may be used if they can be shown to lead to the same results.

Note 2 to entry: It generally means a type of data format to draw figures using CAD board data.

3.8

design document

documentation of information necessary in circuit board design

3.9

device arrangement information

information that includes the position, the shape and attributes of the embedding device included in the net information

3.10

device embedded substrate

substrate in which an active device(s) (semiconductor device) and/or passive device(s) (e.g. resistor, capacitor) is formed using thick-film technology or by embedding it within the substrate

3.11

FLIP chip

FC

leadless monolithic circuit element structure that electrically and mechanically interconnects to a printed board by conductive bumps

3.12

Gerber

type of data format that consists of aperture selection and operation commands and dimensions in X- and Y-coordinates

Note 1 to entry: The data is generally used to direct a photo-plotter in generating photo-plotted artwork.

Note 2 to entry: Gerber is the trade name of a product supplied by Ucamco. This information is given for the convenience of users of this document and does not constitute an endorsement by IEC of the product named. Equivalent products may be used if they can be shown to lead to the same results.

3.13

interposer

material placed between two surfaces giving electrical insulation, redistribution of electrical connections, mechanical strength and/or controlled mechanical and thermal separation between the two surfaces

Note 1 to entry: An interposer may be used as a means for redistributing electrical connections and/or allowing for different thermal expansions between adjacent surfaces.

3.14**land
pad**

portion of a conductive pattern usually used for the connection and/or attachment of components

3.15**land definition**

maintenance of a shape of specific land, pad, solder resist and others

3.16**layer definition**

combination of physical information of shape and construction and logic information giving design and production units

3.17**layer map**

map showing the relation between devices and the board, the devices being arranged on the board

3.18**library**

database of design information based on a design document, to be used in board CAD

3.19**logical layer**

layer that can be arbitrarily formed in the event that it is difficult to physically express a layer in a design

<https://standards.iteh.ai/catalog/standards/sist/02f58227-12d7-44e0-8fc5-2f3058383e71/iec-62878-2-5-2019>

Note 1 to entry: It is possible to relate it to a physical layer.

Note 2 to entry: It is different from the layers in a multi-layer substrate.

3.20**micro-electro-mechanical system****MEMS**

system integrating micro-machine, mechanical elements, sensor, actuator, and electronic circuit into one module

3.21**net information**

device pin construction and wiring pattern in this PAS

3.22**package information**

shapes of board and devices when they have package shape patterns in this document

3.23**PoP****package on package**

single or multiple package(s) mounted on a package of a single chip or multiple chips as single package

3.24**physical layer**

layer consisting of a physical layer construction and structure

3.25

port information

information of figures and names of external terminals of a device or a substrate with terminals

3.26

structure

total structure of a device embedded substrate and/or surface device mounted to the substrate

3.27

SiP

system in a package

multi-chip package (MCP) that performs a system function

3.28

thermal land

heat energy may leak to outside of a land/through-hole when a device is soldered on a large pattern such as power supply or ground. A cut is often made around such a soldering point to prevent thermal dissipation

3.29

through silicon via

TSV

hole made in a silicon chip and filled with metal to electrically connect upper and lower side of the chip for 3D stacking package

3.30

via definition

via that is used as an interlayer connection, but in which there is no intention to insert a component lead or other reinforcing material

3.31

virtual layer

name of the layer connecting conductor layers when a device is embedded

Note 1 to entry: It corresponds to the connection point of a device terminal specified in IEC TS 62678-2-3.

3.32

wire bonding

WB

micro-bonding between a die and base material, lead frame, etc.

4 Data definition

4.1 Flow chart design of device embedded substrate

Figure 1 shows the design flow of a device embedded substrate. The design data can be directly sent to a board manufacturing system using this format, or can be converted to CAM data and then be used in production. The data contain 3D information of coordinates and shapes of devices used. It is possible to check the status of device embedding in a board, and also make it a common knowledge in production know-how of a production line.

This file format describes the detailed 3D information of the following electronic circuit boards, including device embedded substrate and SiP (system in package), and makes it possible to use necessary information from the stage of design to the fabrication of products.

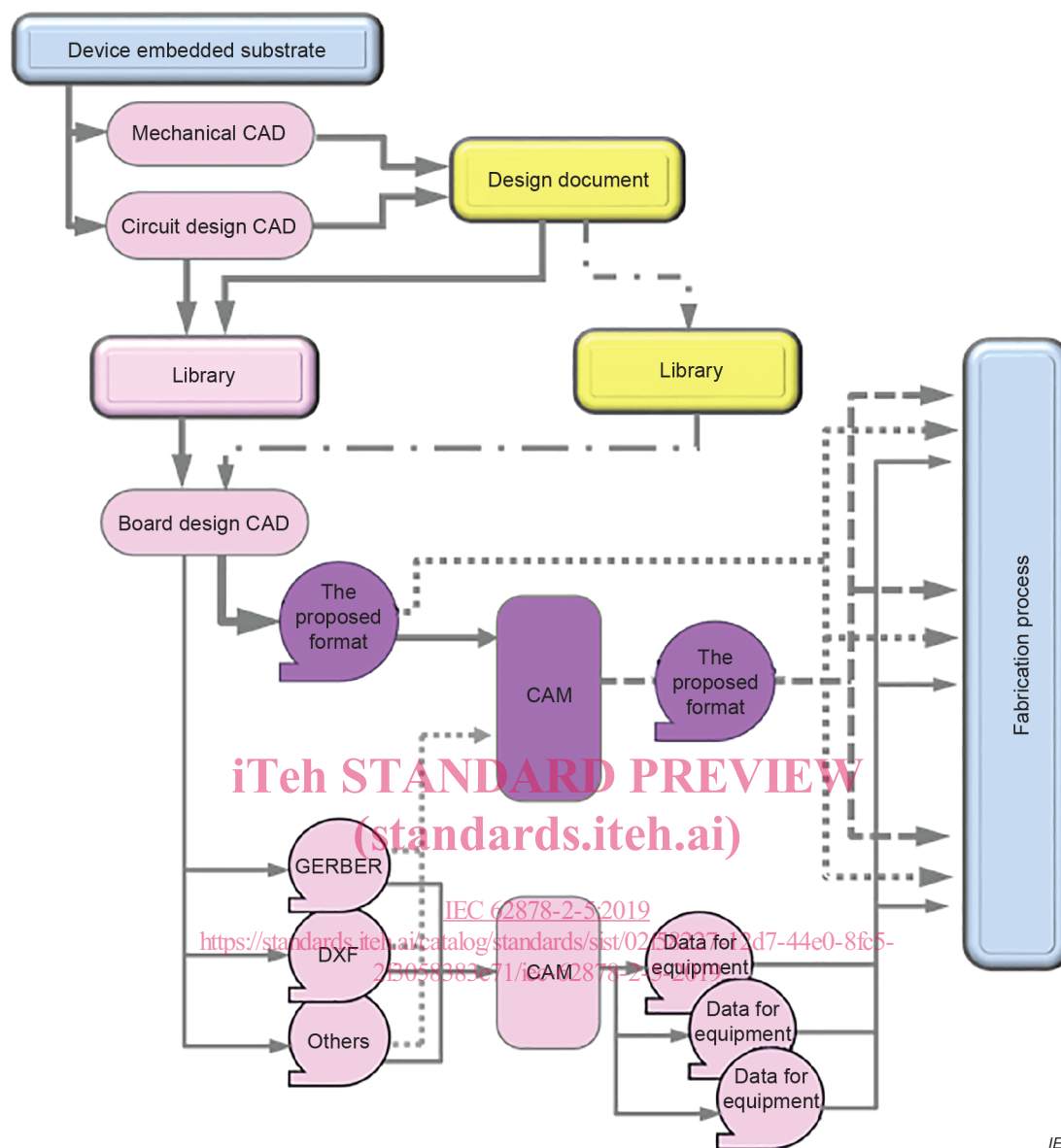
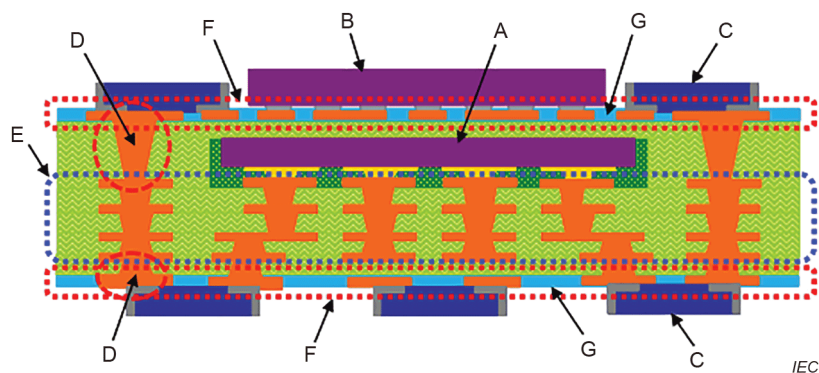


Figure 1 – Flow chart of design of device embedded substrate

4.2 Applicable range

4.2.1 Product

It is possible to maintain the following design information of a device embedded substrate as shown in Figure 2.



A	Embedded active device	E	Inner pattern
B	Surface mounted active device	F	Surface pattern
C	Surface mounted passive device	G	Solder resist
D	Layer connecting via		

Figure 2 – General structure of device embedded substrate

4.2.2 Process

The format describes, maintained and available information of each stage in production as described in Table 1:

- 1) design,
- 2) simulation,
- 3) substrate fabrication,
- 4) device embedding,
- 5) test.

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Table 1 – Required information

Process	Holding data	Available data
Design	Circuit Components Shape of the board Board structure Design/Production rule (for check)	Limited condition Net list
Simulation	Circuit Characteristics of components Board properties (materials) Board structure Art work	Electrical properties Thermal properties Mechanical properties Electronic properties Additional information in production
Substrate fabrication	Art work Drilling Symbol marks Panel format	Equipment Additional information in production
Device embedding	Component shape Embedding position Interconnection terminals Symbol marks	Equipment Relative positions of component Component list
Test	Art work Component shape Component position Terminal information Marks	Electrical test equipment Video image inspection

4.3 Features

4.3.1 General

The data format has the following characteristics:

- 1) can contain the structure of the device embedded substrate specified in IEC TS 62678-2-3;
- 2) can contain information of SiP in general (chip stack, PoP TSV, wire bonding, FLIP chip, interposer, etc.);
- 3) holds design data of terminal positions of embedding device in a virtual layer specified in IEC TS 62678-2-3;
- 4) information on the internal structure of devices such as SiP, which cannot be described as a structure of a device embedded substrate and of a terminal structure as 3D design data;
- 5) seamless keeping of design data of devices having different levels, such as SiPs, and of embedding substrate.

4.3.2 Device embedded substrate structure

It is possible to keep and illustrate the 3D structure of the device embedded substrate as shown in Figure 3. It is also possible to check its 3D structure.